

Please amend the present application as follows:

Title

The following is a copy of Applicant's title that identifies language being added with underlining ("____") and language being deleted with strikethrough ("——"), as is applicable:

METHOD FOR TESTING ANALOG CIRCUITS

Specification

The following is a copy of Applicant's specification that identifies language being added with underlining ("____") and language being deleted with strikethrough ("—"), as is applicable:

Page 28, lines 1 through 5.

Fitness evaluation: One measurement in a particular segment of the PWL transient waveform is suade. Hence, ~~he~~ the total number of measurements is equal to the string length N. The fitness is equal to the sum of absolute value of the sensitivities of the measurements to the process parameters for the critical circuit instances.

Page 30, line 14 through page 31, line 1.

It is to be noted that not all the 44 circuits with uncertain test outcome were subjected to all the specification tests. From the table it can be seen that bias currents of 37, f_3 dB of five, phase margin of one and gain margin of 48 circuits are to be measured. Thus, in worst case, only 91 ~~performane~~ performance parameters must be measured to correctly classify 97.5% of the CUTS.